

<b>Notice of References Cited</b>	Application/Control No. 09/786,680	Applicant(s)/Patent Under Reexamination ONISHI ET AL.	
	Examiner Cheukfan Lee	Art Unit 2622	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,496,285	12-2002	Fujimoto et al.	358/475
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	J	US-			
	K	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

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